

October 1994 Revised August 1999

74F1071

18-Bit Undershoot/Overshoot Clamp and ESD Protection Device

General Description

The 74F1071 is an 18-bit undershoot/overshoot clamp which is designed to limit bus voltages and also to protect more sensitive devices from electrical overstress due to electrostatic discharge (ESD). The inputs of the device aggressively clamp voltage excursions nominally at 0.5V below and 7V above ground.

Features

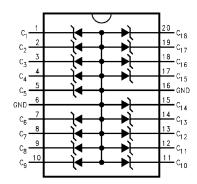
- 18-bit array structure in 20-pin package
- FAST® Bipolar voltage clamping action
- Dual center pin grounds for min inductance
- Robust design for ESD protection
- Low input capacitance
- Optimum voltage clamping for 5V CMOS/TTL applications

Ordering Code:

Order Number	Package Number	Package Description				
74F1071SC	M20B	20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300 Wide				
74F1071MSA	MSA20	20-Lead Shrink Small Outline Package (SSOP), EIAJ TYPE II, 5.3mm Wide				
74F1071MTC	MTC20	20-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 4.4mm Wide				

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

Connection Diagram



Note: Simplified Component Representation

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Absolute Maximum Ratings(Note 1)

Storage Temperature -65°C to +150°C -65°C to +125°C Ambient Temperature under Bias Junction Temperature under Bias -65°C to $+150^{\circ}\text{C}$ Input Voltage (Note 2) -0.5V to +6V

Input Current (Note 2) -200 mA to +50 mA ESD (Note 3)

Human Body Model

(MIL-STD-883D method 3015.7) ±10 kV IEC 801-2 ±6 kV

Machine Model (EIAJIC-121-1981) ±2 kV

DC Latchup Source Current

(JEDEC Method 17) ±500 mA

Package Power Dissipation @+70°C

SOIC Package 800 mW

Recommended Operating Conditions

Free Air Ambient Temperature 0°C to +70°C 0V to 5.25 $V_{\mbox{\scriptsize DC}}$ Reverse Bias Voltage

Thermal Resistance (θ_{JA} in Free Air)

SOIC Package 100°C/W SSOP Package 110°C/W

Note 1: Absolute maximum ratings are DC values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: Voltage ratings may be exceeded if current ratings and junction temperature and power consumption ratings are not exceeded.

Note 3: ESD Rating for Direct contact discharge using ESD Simulation

Tester. Higher rating may be realized in the actual application.

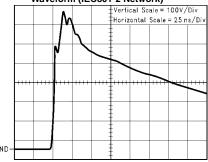
DC Electrical Characteristics

Symbol	Parameter	T _A = +25°C			$T_A = 0$ °C to +70°C		Units	Conditions
	i diameter	Min	Тур	Max	Min	Max	Units	Conditions
I _{IH}	Input HIGH Current		1.5	10		50		V _{IN} = 5.25V; Untested Input @ GND
			3	20		100	μΑ	V _{IN} = 5.5V; Untested Input @ GND
V _Z	Reverse Voltage	6.6	6.9	7.2	5.9	7.7	V	I _Z = 1 mA; Untested Inputs @ GND
			7.1	7.5		8.0	V	I _Z = 50 mA; Untested Inputs @ GND
V _F	Forward Voltage	-0.3	-0.6	-0.9	-0.3	-0.9	V	I _F = -18 mA; Untested Inputs @ 5V
		-0.5	-1.1	-1.5	-0.5	-1.5	V	$I_F = -200$ mA; Untested Inputs @ 5V
I _{CT}	Adjacent Input Crosstalk			3			%	
C _{IN}	Input Capacitance	25				pF	$V_{BIAS} = 0 V_{DC}$ $V_{BIAS} = 5 V_{DC}$	
	(small signal @ 1 MHz)		13				PΓ	$V_{BIAS} = 5 V_{DC}$

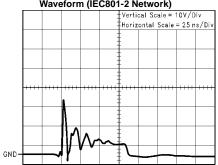
DC Electrical Characteristics Typical Forward and Reverse V/I Characteristics HOR = 1V/Div VER = 5 mA/Di 25° 0 mA 0٧ 5٧ **Typical Reverse Conduction Typical Forward Conduction** Characteristics Characteristics HOR = 0.25V/Div VER = 5 mA/Div HOR = 0.1V/Div VER = 5 mA/Div 70°--50 mA Digitizing ESD Tester Oscilloscope 10X RG-188A/U 500hm Coax Attenuator **\$**50Ω **Used only for open socket high voltage measurements 74F1071SC ESD Network CZ RΖ Human Body Model 1500Ω Simulated ESD Voltage Clamping Test Circuit 100 pF IEC 801-2 150 pF 330Ω

DC Electrical Characteristics (Continued)

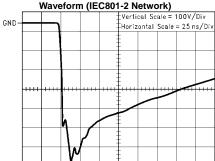
Unclamped + 1 KV ESD Voltage Waveform (IEC801-2 Network)

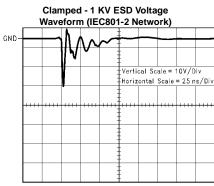


Clamped + 1 KV ESD Voltage Waveform (IEC801-2 Network)

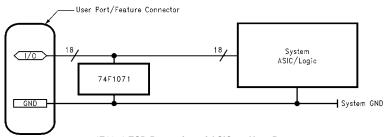


Unclamped - 1 KV ESD Voltage Waveform (IEC801-2 Network)

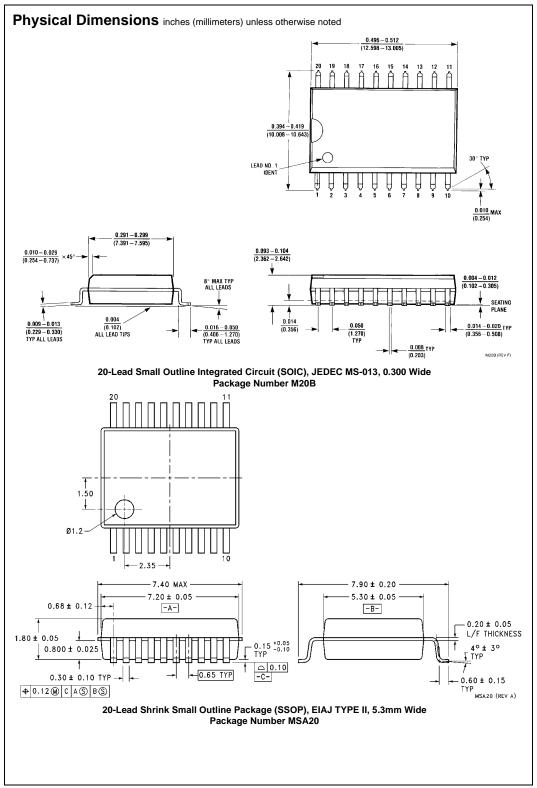




Typical Application



74F1071 ESD Protection of ASIC on User Port



Physical Dimensions inches (millimeters) unless otherwise noted (Continued) -0.20 20 7. ۶ځ 16 64 4.4±0.1 -B-3.2 ₩0.42 0.2 C B A PIN #1 IDENT. LAND PATTERN RECOMMENDATION O.1 C SEE DETAIL A -0.90+0.15 -0.10 0.09-0.20 0.1±0.05 0.65 0.19-0.30 | \$\P\$ | 0.1000 | A| B\$\P\$ | C\$\P\$ | 12.00° R0.09min GAGE PLANE DIMENSIONS ARE IN MILLIMETERS NOTES: 0.25<u>|</u> SEATING PLANE A. CONFORMS TO JEDEC REGISTRATION M□-153, VARIATION AC, REF NOTE 6. DATE 7/93. -0.6±0.1-R0.09mln B. DIMENSIONS ARE IN MILLIMETERS. C. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLDS FLASH, AND TIE BAR EXTRUSIONS. DETAIL A

20-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 4.4mm Wide Package Number MTC20

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